

<b>Notice of References Cited</b>	Application/Control No. 09/994,010	Applicant(s)/Patent Under Reexamination TANIKAWA ET AL.	
	Examiner A. Dexter Tugbang	Art Unit 3729	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Chen et al., "Development and Electrical Characterization of Lead Zirconate Titanate Thick Films on Silicon Substrates", Proceedings on the 9 <sup>th</sup> IEEE Symposium on Applications of Ferroelectrics, 1994, August 1994, pages 495-498.
	V	
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